S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/630,730	CHINA, HIROSHI	
Examiner	Art Unit	
Edgardo San Martin	2937	

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181	176,156 199,153 163,164 165,191	6/28/2005	ESM
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	DATE	EXMR
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